

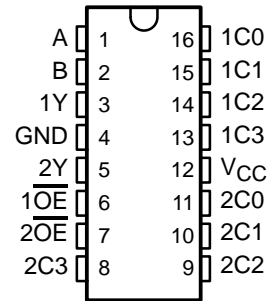
74ACT11352

DUAL 4-LINE TO 1-LINE DATA SELECTOR/MULTIPLEXER

SCAS168 – DECEMBER 1991 – REVISED APRIL 1993

- Inputs Are TTL-Voltage Compatible
- Permit Multiplexing From N Lines to 1 Line
- Perform Parallel-to-Serial Conversion
- Strobe Line Provided for Cascading (N Lines to N Lines)
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Pin Configurations Minimize High-Speed Switching Noise
- **EPIC™** (Enhanced-Performance Implanted CMOS) 1- μ m Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, and Standard Plastic 300-mil DIPs

D OR N PACKAGE
(TOP VIEW)



description

Each of these data selectors/multiplexers contains inverters and drivers to supply full binary-decoding data selection to the AND-OR gates. Separate strobe output-enable (\overline{OE}) inputs are provided for each of the two four-line sections.

The 74ACT11352 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE
(each multiplexer)

SELECT INPUTS		DATA INPUTS				STROBE \overline{OE}	OUTPUT Y
B	A	C0	C1	C2	C3		
X	X	X	X	X	X	H	H
L	L	L	X	X	X	L	H
L	L	H	X	X	X	L	L
L	H	X	L	X	X	L	H
L	H	X	H	X	X	L	L
H	L	X	X	L	X	L	H
H	L	X	X	H	X	L	L
H	H	X	X	X	L	L	H
H	H	X	X	X	H	L	L

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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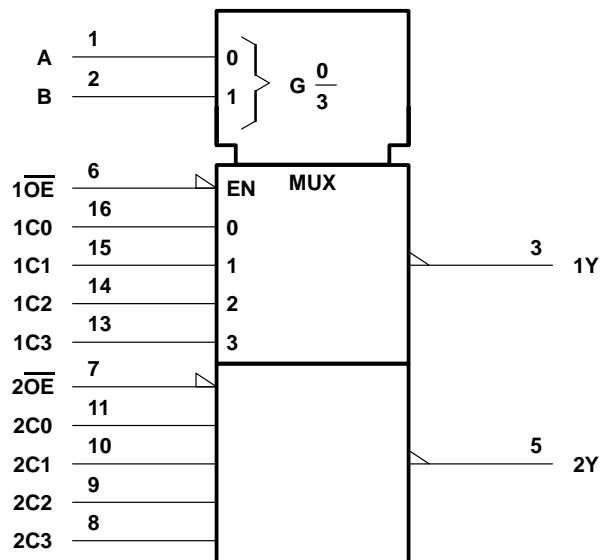
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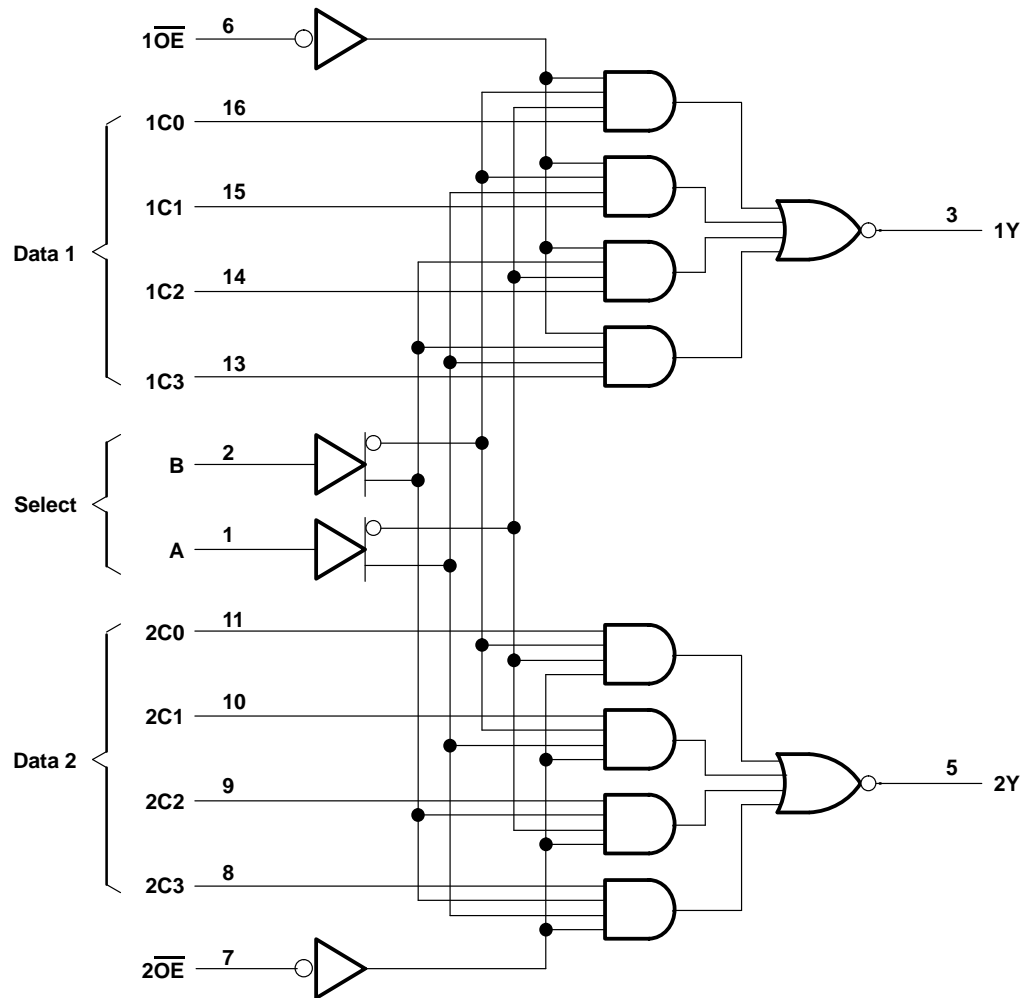
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V_{CC} or GND pins	±100 mA
Storage temperature range	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
V_I	Input voltage	0	V_{CC}		V
V_O	Output voltage	0	V_{CC}		V
I_{OH}	High-level output current			-24	mA
I_{OL}	Low-level output current			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	ns/V
T_A	Operating free-air temperature	-40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	$T_A = 25^\circ\text{C}$			MIN	MAX	UNIT
			MIN	TYP	MAX			
V_{OH}	$I_{OH} = -50\ \mu\text{A}$	4.5 V	4.4			4.4		V
		5.5 V	5.4			5.4		
	$I_{OH} = -24\ \text{mA}$	4.5 V	3.94			3.8		
		5.5 V	4.94			4.8		
	$I_{OH} = -75\ \text{mA}^\dagger$	5.5 V				3.85		
V_{OL}	$I_{OL} = 50\ \mu\text{A}$	4.5 V			0.1		0.1	V
		5.5 V			0.1		0.1	
	$I_{OL} = 24\ \text{mA}$	4.5 V			0.36		0.44	
		5.5 V			0.36		0.44	
	$I_{OL} = 75\ \text{mA}^\dagger$	5.5 V					1.65	
I_I	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		± 1	μA
I_{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μA
ΔI_{CC}^\ddagger	One input at 3.4 V, Other inputs at V_{CC} or GND	5.5 V			0.9		1	mA
C_i	$V_I = V_{CC}$ or GND	5 V		3.5				pF

† Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

‡ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC} .

switching characteristics over recommended operating free-air temperature range, $V_{CC} = 5\ \text{V} \pm 0.5\ \text{V}$ (unless otherwise noted) (see Figure 1)

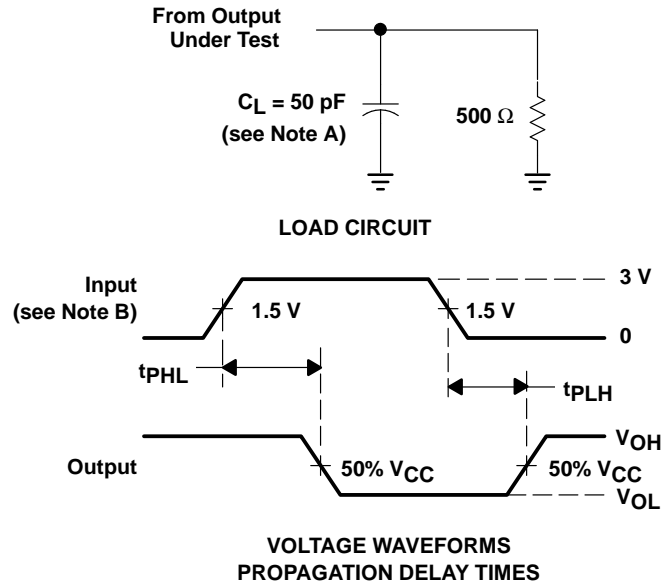
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$T_A = 25^\circ\text{C}$			MIN	MAX	UNIT
			MIN	TYP	MAX			
t_{PLH}	A or B	Y	2	5.3	7.8	2	8.6	ns
t_{PHL}			2.9	6.7	9.3	2.9	10.7	
t_{PLH}	Any C	Y	2.1	5	7.2	2.1	8.2	ns
t_{PHL}			3.3	6.3	7.8	3.3	8.9	
t_{PLH}	OE	Y	2	4.2	5.5	2	6	ns
t_{PHL}			2.5	5.5	7.6	2.5	8.3	



operating characteristics, $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance	$C_L = 50\text{ pF}$, $f = 1\text{ MHz}$	30	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

B. Input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r = 3\text{ ns}$, $t_f = 3\text{ ns}$.

C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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